

DECLARATION FOR PATENT APPLICATION

02S0045

As a below named inventor, I declare:
that I verily believe myself to be the original, first and sole (if only one
individual inventor is listed below) or an original, first and joint inventor
(if more than one individual inventor is listed below) of the invention in

PROFILE MEASURING METHOD AND MEASUREMENT APPARATUS USING INTERFERENCE
OF LIGHT

the specification of which is attached hereto unless the following box is
checked.

☐ was filed on _____ as United States Application
or PCT International Application No. _____, and
was amended on _____ (if applicable).

I hereby state that I have reviewed and understand the contents of the above
identified specification, including the claims, as amended by any amendment
referred to above.

I acknowledge the duty to disclose information of which is material to pat-
entability as defined in 37 CFR 1.56.

I hereby claim foreign priority benefits under 35 U.S.C. 119(a)-(d) or 365
(b) of any foreign application(s) for patent or inventor's certificate, or
35 U.S.C. 365(a) of any PCT International application which designated at
least one country other than the United States, listed below and have also
identified below any foreign application for patent or inventor's certifi-
cate, or PCT International application having a filing date before that of the
application on which priority is claimed:

| <u>Country</u> | <u>Category</u> | <u>Application No.</u> | <u>Filing Date</u> | <u>Priority Claim</u> |
|----------------|-----------------|------------------------|--------------------|-----------------------|
| Japan | Patent | 2001-267786 | September 4, 2001 | Yes |

I hereby appoint the registrants of Oblon, Spivak, McClelland,
Maier & Neustadt, P.C., Fourth Floor, 1755 Jefferson Davis Highway,
Arlington, Virginia 22202, Customer No. 22850, or any one of them.
Send correspondence to Oblon, Spivak, McClelland, Maier & Neustadt,
P.C., Fourth Floor, 1755 Jefferson Davis Highway, Arlington, Virginia
22202, Telephone No. (703) 413-3000.

I declare further that all statements made herein of my own knowledge are
true and that all statements made on information and belief are believed to
be true; and further that these statements were made with the knowledge that
willful false statements and the like so made are punishable by fine or im-
prisonment, or both, under Section 1001 of Title 18 of the United States
Code and that such willful false statements may jeopardize the validity of
the application or any patent issued thereon.

DECLARATION FOR PATENT APPLICATION

I declare further that my citizenship, residence and mailing address are as stated below next to my name:

Inventor: (Signature)

Date

Residence and mailing address

Date: February 15, 2002

Masaaki Adachi

Masaaki Adachi

Citizen of: Japan

53-6, Wakamatsu-machi,
Kanazawa-shi, Ishikawa-ken, Japan

Date:

Citizen of: Japan

Date:

Citizen of: Japan

Date:

Citizen of: Japan

Date:

Citizen of: Japan

Date:

Citizen of: Japan

Date:

Citizen of: Japan

Date:

Citizen of: Japan

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DOCKET NO.: 220102US2

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Masaaki ADACHI

SERIAL NO.: NEW APPLICATION

FILED: HEREWITH

FOR: PROFILE MEASURING METHOD AND MEASUREMENT APPARATUS USING
INTERFERENCE OF LIGHT

REQUEST FOR SMALL ENTITY STATUS

This application qualifies for small entity status.

Respectfully Submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.

Date: _____

3/1/02


Marvin J. Spivak

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C. Irvin McClelland
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